


<b>Search Notes</b>  	<b>Application/Control No.</b>  10799771	<b>Applicant(s)/Patent Under Reexamination</b>  CHO ET AL.
	<b>Examiner</b>  Kwiecinski, Ryan D	<b>Art Unit</b>  3635

SEARCHED			
Class	Subclass	Date	Examiner
52	172	2/15/2007	RDK
	171.2	2/13/2007	RDK
	171.1	2/13/2007	RDK
	171.3	2/14/2007	RDK
	204.5	2/14/2007	RDK
219	213	2/15/2007	RDK
	203	2/14/2007	RDK

SEARCH NOTES		
Search Notes	Date	Examiner
Class 52 Search	2/14/2007	RDK
Class 219 Search	2/14/2007	RDK
BRS Text Search (See attached)	2/14/2007	RDK
PALM Inventor Search	2/15/2007	RDK
Updated Search	7/2/2007	RDK
Updated Search	12/13/2007	RDK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner